

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OGAWA ET AL.	
		Examiner Diane Yabut	Art Unit 3734	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,013,084	01-2000	Ken et al.	606/108
*	B	US-2004/0034363	02-2004	Wilson et al.	606/108
*	C	US-2004/0002732	01-2004	Teoh et al.	606/200
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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